

Notice of References Cited	Application/Control No. 10/580,401	Applicant(s)/Patent Under Reexamination CHEN ET AL.	
	Examiner MEWALE AMBAYE	Art Unit 2472	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2006/0182119	08-2006	Li et al.	370/395.52
*	B	US-2003/0084089	05-2003	Kurose et al.	709/200
*	C	US-7,215,640	05-2007	Matsubara, Daisuke	370/235
*	D	US-2003/0076829	04-2003	Rabie et al.	370/391
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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	N					
	O					
	P					
	Q					
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	I					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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